# **BLF6G20-45**

# **UHF power LDMOS transistor**

Rev. 01 — 20 February 2006

**Objective data sheet** 

### 1. Product profile

### 1.1 General description

45 W LDMOS power transistor for base station applications at frequencies from 1800 MHz to 2000 MHz.

Table 1: Typical performance

RF performance at  $T_{case}$  = 25 °C in a common source class-AB production test circuit.

Mode of operation	f	V <sub>DS</sub>	P <sub>L(AV)</sub>	Gp	η <sub>D</sub>	ACPR
	(MHz)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	1805 to 1880	28	2.5	17	14	-50 <sup>[1]</sup>

<sup>[1]</sup> Test signal: 3GPP; test model 1; 64 DPCH; PAR = 7.5 dB at 0.01 % probability on CCDF per carrier; carrier spacing 5 MHz

#### **CAUTION**



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

#### 1.2 Features

- Typical 2-carrier W-CDMA performance at frequencies of 1805 MHz and 1880 MHz, a supply voltage of 28 V and an I<sub>Dq</sub> of 350 mA:
  - ◆ Average output power = 2.5 W
  - Power gain = 17 dB (typ)
  - ◆ Efficiency = 14 %
  - ◆ ACPR = -50 dBc
- Easy power control
- Integrated ESD protection
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (1800 MHz to 2000 MHz)
- Internally matched for ease of use

#### 1.3 Applications

■ RF power amplifiers for W-CDMA base stations and multi carrier applications in the 1800 MHz to 2000 MHz frequency range.



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## 2. Pinning information

Table 2: Pinning

Pin	Description	Simplified outline	Symbol
1	drain		<tbd></tbd>
2	gate		
3	source	[1]	

<sup>[1]</sup> Connected to flange

# 3. Ordering information

**Table 3: Ordering information** 

Type number	Package	e	
	Name	Description	Version
BLF6G20-45	-	flanged ceramic package; 2 mounting holes; 2 leads	SOT608A

### 4. Limiting values

Table 4: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage		-	65	V
$V_{GS}$	gate-source voltage		-0.5	+13	V
$I_D$	drain current		-	<tbd></tbd>	Α
T <sub>stg</sub>	storage temperature		-65	+150	°C
Tj	junction temperature		-	225	°C

### 5. Thermal characteristics

Table 5: Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-case)}}$	thermal resistance from junction to case	$T_{case} = 80 ^{\circ}C;$ $P_{L} = < tbd>$	<tbd></tbd>	<tbd></tbd>	<tbd></tbd>	K/W

### 6. Characteristics

**Table 6: Characteristics** 

 $T_i = 25 \,^{\circ}C$  per section; unless otherwise specified

Parameter drain-source breakdown voltage gate-source threshold voltage	Conditions $V_{GS} = 0 \text{ V; } I_{D} = 0.5 \text{ mA}$	Min 65	Typ -	Max -	Unit V
voltage		65	-	-	V
gate-source threshold voltage	\/ 10\\\.I 60 m\				
	$v_{DS} = 10 \text{ v}, I_D = 60 \text{ mA}$	<tbd></tbd>	1.6	<tbd></tbd>	V
gate-source quiescent voltage	$V_{DS} = 28 \text{ V}; I_D = 300 \text{ mA}$	<tbd></tbd>	2	<tbd></tbd>	V
drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	1.5	μΑ
drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	9	11	-	Α
gate leakage current	$V_{GS} = 13 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	150	nΑ
forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 3 \text{ A}$	-	<tbd></tbd>	-	S
drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 2.1 \text{ A}$	-	0.25	<tbd></tbd>	Ω
feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V};$ f = 1 MHz	-	<tbd></tbd>	-	pF
() ()	gate-source quiescent voltage drain leakage current drain cut-off current gate leakage current forward transconductance drain-source on-state resistance	gate-source quiescent voltage $V_{DS} = 28 \text{ V}; I_D = 300 \text{ mA}$ drain leakage current $V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$ drain cut-off current $V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$ $V_{DS} = 10 \text{ V}$ gate leakage current $V_{GS} = 13 \text{ V}; V_{DS} = 0 \text{ V}$ forward transconductance $V_{DS} = 10 \text{ V}; I_D = 3 \text{ A}$ drain-source on-state $V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 2.1 \text{ A}$ feedback capacitance $V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V};$	gate-source quiescent voltage $V_{DS} = 28 \text{ V}; I_D = 300 \text{ mA}$ drain leakage current $V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$ - drain cut-off current $V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ 9 $V_{DS} = 10 \text{ V}$ - gate leakage current $V_{GS} = 13 \text{ V}; V_{DS} = 0 \text{ V}$ - forward transconductance $V_{DS} = 10 \text{ V}; I_D = 3 \text{ A}$ - drain-source on-state $V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ - feedback capacitance $V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V};$ -	gate-source quiescent voltage $V_{DS} = 28 \text{ V}; I_D = 300 \text{ mA}$ <b><tbd>2</tbd></b> drain leakage current $V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$ drain cut-off current $V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ 9 11 $V_{DS} = 10 \text{ V}$ gate leakage current $V_{GS} = 13 \text{ V}; V_{DS} = 0 \text{ V}$ forward transconductance $V_{DS} = 10 \text{ V}; I_D = 3 \text{ A}$ - <b><tbd>4tbd&gt;</tbd></b> drain-source on-state $V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ - 0.25 resistance $V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V};$ - <b><tbd>4tbd&gt;</tbd></b>	gate-source quiescent voltage $V_{DS} = 28 \text{ V}; I_D = 300 \text{ mA}$ <b><tbd></tbd></b> 2 <b><tbd></tbd></b> 4tbd> 2 <b><tbd></tbd></b> 2 <b><tbd></tbd></b> 4tbd> 3.75 V; $V_{DS} = 28 \text{ V}$

### 7. Application information

**Table 7: Application information** 

Mode of operation: 2-carrier W-CDMA; PAR 7.5 dB at 0.01 % probability on CCDF; 3GPP test model 1; 1-64 PDPCH;  $f_1$  = 1807.5 MHz;  $f_2$  = 1812.5 MHz;  $f_3$  = 1872.5 MHz;  $f_4$  = 1877.5 MHz; RF performance at  $V_{DS}$  = 28 V;  $I_{Dq}$  = 2× 900 mA;  $T_{case}$  = 25 °C; unless otherwise specified; in a class-AB production test circuit

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$P_{L(AV)}$	average output power		-	2.5	-	W
Gp	power gain	$P_{L(AV)} = 2.5 \text{ W}$	<tbd></tbd>	17	-	dB
$\eta_{D}$	drain efficiency	$P_{L(AV)} = 2.5 \text{ W}$	<tbd></tbd>	14	-	%
IMD3	third order intermodulation distortion	$P_{L(AV)} = 2.5 \text{ W}$	-	<tbd></tbd>	<tbd></tbd>	dBc
ACPR	adjacent channel power ratio	$P_{L(AV)} = 2.5 \text{ W}$	-	-50	<tbd></tbd>	dBc

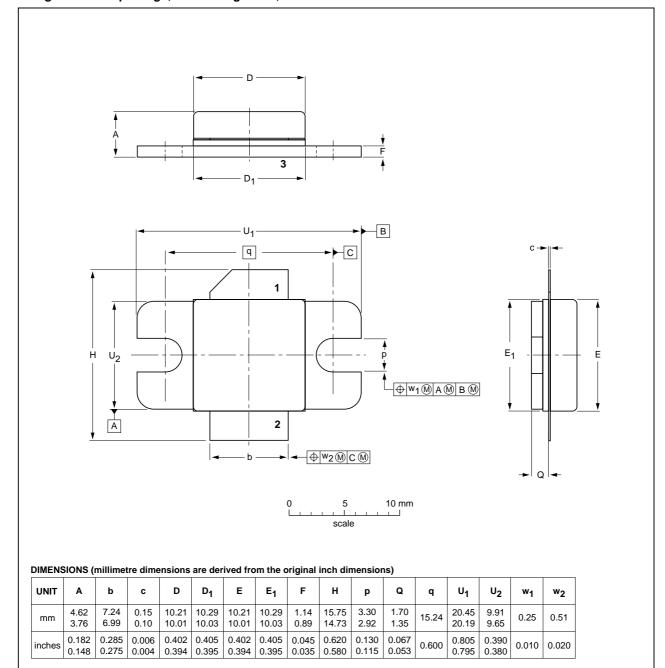
### 7.1 Ruggedness in class-AB operation

The BLF6G20-45 is capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions:  $V_{DS}$  = 28 V;  $I_{Dq}$  = 350 mA;  $P_L$  = 45 W (CW); f = 1880 MHz.

### 8. Package outline

#### Flanged ceramic package; 2 mounting holes; 2 leads

SOT608A



OUTLINE		REFERENCES		EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT608A						<del>01-02-22</del> 02-02-11

Fig 1. Package outline SOT608A



### 9. Abbreviations

Table 8: Abbreviations

Acronym	Description
3GPP	Third Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
LDMOS	Laterally Diffused Metal Oxide Semiconductor
PAR	Peak-to-Average power Ratio
PDPCH	transmission Power of the Dedicated Physical CHannel
RF	Radio Frequency
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access



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# 10. Revision history

### Table 9: Revision history

Document ID	Release date	Data sheet status	Change notice	Doc. number	Supersedes
BLF6G20-45_1	20060220	Objective data sheet	-	-	-



Level	Data sheet status [1]	Product status [2] [3]	Definition
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